

Identification and rejuvenation of NBTI-critical logic paths in nanoscale circuits

Jenihhin, Maksim; Squillero, Giovanni; **Tihhomirov, Valentin**; **Kostin, Sergei**; **Raik, Jaan**; **Ubar, Raimund-Johannes** Journal of electronic testing : theory and applications (JETTA) 2016 / p. 273-289 : ill <https://doi.org/10.1007/s10836-016-5589-x> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

On NBTI-induced aging analysis in IEEE 1687 reconfigurable scan networks

Damljanovic, Aleksa; Squillero, Giovanni; **Gürsoy, Cemil Cem**; **Jenihhin, Maksim** VLSI-SoC 2019 : 27th IFIP/IEEE International Conference on Very Large Scale Integration : [proceedings] 2019 / p. 335-340 : ill <https://doi.org/10.1109/VLSI-SoC.2019.8920313>

Post-silicon validation of IEEE 1687 reconfigurable scan networks

Damljanovic, Aleksa; **Jutman, Artur**; Squillero, Giovanni; **Tšertov, Anton** 2019 IEEE European Test Symposium (ETS) : proceedings 2019 / 6 p. : ill <https://doi.org/10.1109/ETS.2019.8791546>

Rejuvenation of NBTI-impacted processors using evolutionary generation of assembler programs

Pellerey, Francesco; **Jenihhin, Maksim**; Squillero, Giovanni; **Raik, Jaan**; Sonza Reorda, Matteo; **Tihhomirov, Valentin**; **Ubar, Raimund-Johannes** 2016 IEEE 25th Asian Test Symposium : 21-24 November 2016, Hiroshima, Japan 2016 / p. 304-309 : ill <https://doi.org/10.1109/ATS.2016.57> [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)